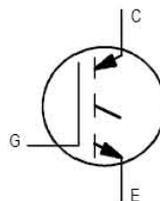


Features

- High short circuit rating optimized for motor control
- Low conduction losses
- High switching speed
- Tighter parameter distribution

$V_{CES}=1200\text{ V}$
 $V_{CE(on)\text{ typ. }}=3,8\text{ V}$
 $@V_{GE}=15\text{V, }I_C=20\text{A}$




N-channel

ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Units	Max
Collector-to-Emitter Voltage	V_{CES}	V	1200
Continuous Collector Current	$I_C @ T_C=25^\circ\text{C}$	A	20
Continuous Collector Current	$I_C @ T_C=100^\circ\text{C}$		10
Pulsed Collector Current ¹	I_{CM}		41
Clamped Inductive Load Current ²	I_{LM}		41
Short Circuit Withstand Time	tsc	μs	10
Maximum Power Dissipation	$P_D @ T_C=25^\circ\text{C}$	W	100
Maximum Power Dissipation	$P_D @ T_C=100^\circ\text{C}$		42
Gate-to-Emitter Voltage	V_{GE}	V	± 20
Operating Junction and Storage temperature Range	T_J T_{STG}	$^\circ\text{C}$	-55 to +150
Soldering Temperature, for 10 seconds		$^\circ\text{C}$	300

THERMAL RESISTANCE

Parameter	Symbol	Units	Min	Typ.	Max
Junction-to-Case	$R_{\theta JC}$	$^\circ\text{C/W}$	-	-	1,2
Case-to-Sink, Flat, Greased Surface	$R_{\theta CS}$		-	0,24	-
Junction-to-Ambient, typical socket mount	$R_{\theta JA}$		-	-	40

ELECTRICAL CHARACTERISTICS (T_j =25 °C)

Parameter	Symbol	Units	Test Conditions	Min	Typ.	Max
Collector-to-Emitter Breakdown Voltage	V _{(BR)CES}	V	V _{GE} = 0V, I _C = 250μA	1200	-	-
Emitter-to-Collector Breakdown Voltage	V _{(BR)ECS}	V	V _{GE} = 0V, I _C = 1A	18	-	-
Breakdown Voltage Temp.Coefficient	ΔV _{(BR)CES} /ΔT _J	V/°C	V _{GE} = 0V, I _C = 2 mA	-	0,2	-
Collector-to-Emitter Saturation Voltage (See figure 2,5)	V _{CE(ON)}	V	V _{GE} = 15V, I _C = 10A	-	3,0	4,0
			V _{GE} = 15V, I _C = 20A	-	3,8	-
			V _{GE} = 15V, I _C = 10A T _J =150°C	-	2,9	-
Gate Threshold Voltage	V _{GE(th)}	V	V _{GE} =V _{CE} , I _C =250 μA	3,0	-	6,0
Threshold Voltage Temp.Coefficient	ΔV _{(GE)th} / ΔT _J	mV/°C	V _{GE} =V _{CE} , I _C =250μA	-	-11	-
Forward Transconductance	g _(fe)	S	V _{CE} = 100V, I _C = 10A	4,3	6,8	-
Zero Gate Voltage Collector Current	I _{CES}	μA	V _{CE} = 1200V, V _{GE} =0V	-	-	250
			V _{CE} = 10V, V _{GE} =0V T _J =25°C	-	-	2,0
			V _{CE} = 1200V, V _{GE} =0V T _J =150°C	-	-	2000
Gate-to-Emitter Leakage Current	I _{GES}	nA	V _{GS} = ±20V			±100

SWITCHING CHARACTERISTICS (T_j =25 °C)

Parameter	Symbol	Units	Test Conditions	Min	Typ.	Max
Total Gate Charge (turn on)	Q _g	nC	V _{GE} = 15V, V _{CC} = 400V, I _C =10A See Figure 8	-	54	80
Gate-to-Emitter Charge (turn on)	Q _{ge}			-	12	14
Gate-to-Collector Charge (turn on)	Q _{gc}			-	24	32
Turn-On Delay Time	t _{d(on)}	ns	V _{CC} =960V, I _C =10A V _{GE} = 15V R _G =23Ω	-	30	-
Rise Time	t _r			-	27	-
Turn-Off Delay Time	t _{d(off)}			-	230	300
Fall Time	t _f			-	130	170
Turn-On Switching Loss	E _{on}	mJ	Energy losses include «tail» See Figure 9,10,14	-	0,66	-
Turn-Off Switching Loss	E _{off}			-	0,94	-
Total Switching Loss	E _{TS}			-	1,6	2,4
Turn-On Delay Time	t _{d(on)}	ns	T _J =150°C V _{CC} =960V, I _C =10A V _{GE} = 15V R _G =23 Ω Energy losses include «tail» See Figure 10,11,14	-	29	-
Rise Time	t _r			-	28	-
Turn-Off Delay Time	t _{d(off)}			-	340	-
Fall Time	t _f			-	350	-
Total Switching Loss	E _{TS}	mJ		-	3,3	-
Input Capacitance	C _{ISS}	pF	V _{GE} = 0V, V _{CC} = 30V, f = 1.0MHz See Figure 7	-	830	-
Output Capacitance	C _{OSS}			-	630	-
Reverse Transfer Capacitance	C _{RSS}			-	16	-

NOTES:

- ¹ Repetitive rating; V_{GE} =20V, pulse width limited by max junction temperature.(Fig.13b)
- ² V_{CC}=80%(V_{CES}), L= 10 μH, V_{GE} = 20V, R_G=23 Ω,(Fig.13a)
- ³ Pulse width ≤80 μs, duty factor ≤0,1%.
- ⁴ Pulse width 5,0μs single short.

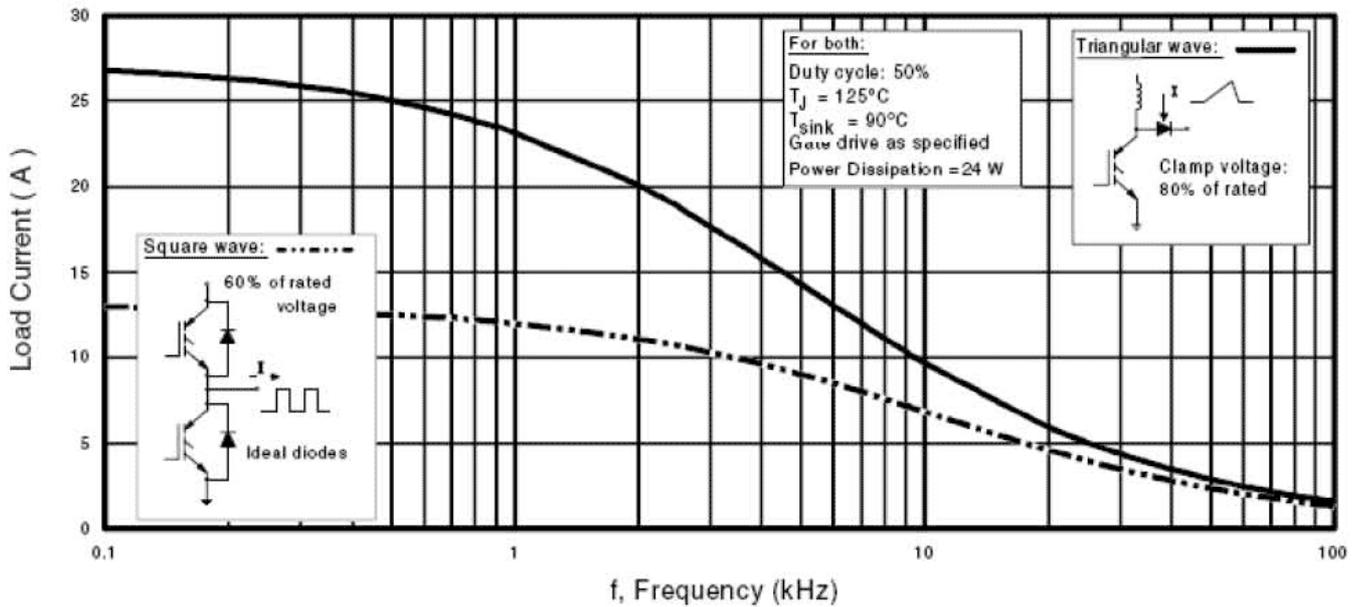


Fig.1- Typical Load Current vs. Frequency
(Load Current= I_{RMS} of fundamental)

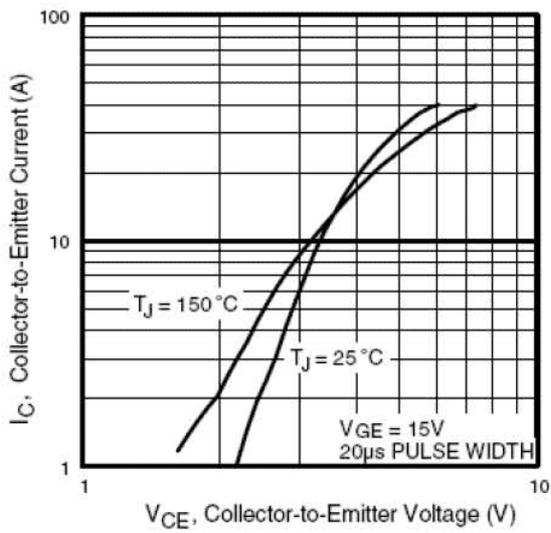


Fig.2-Typical Output Characteristics

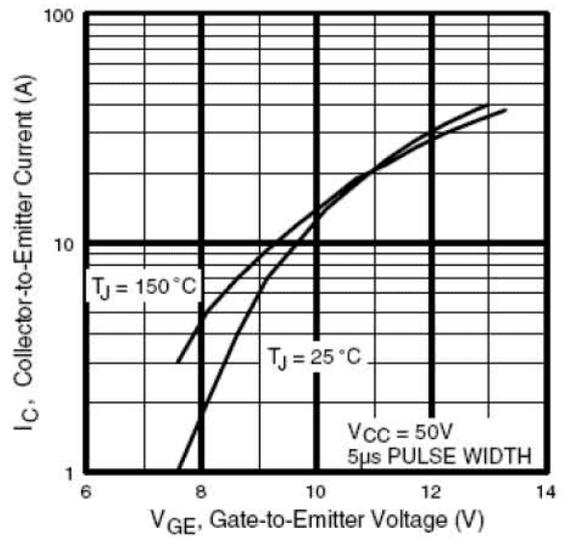


Fig.3-Typical Transfer Characteristics

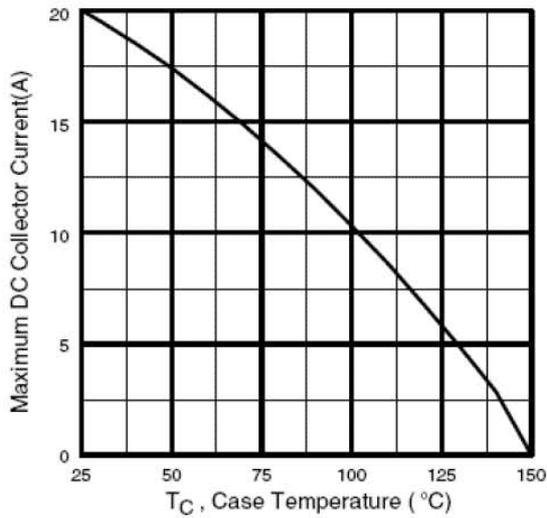


Fig.4-Maximum Collector Current vs. Case Tempertaure

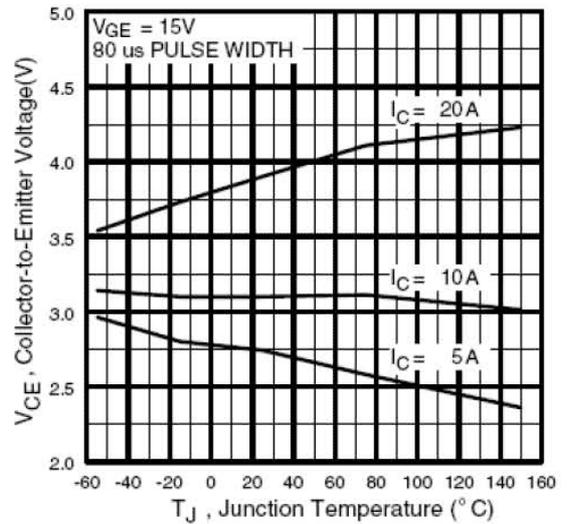


Fig.5 – Typical Collector-to-Emitter Voltage Vs. Junction Temperature

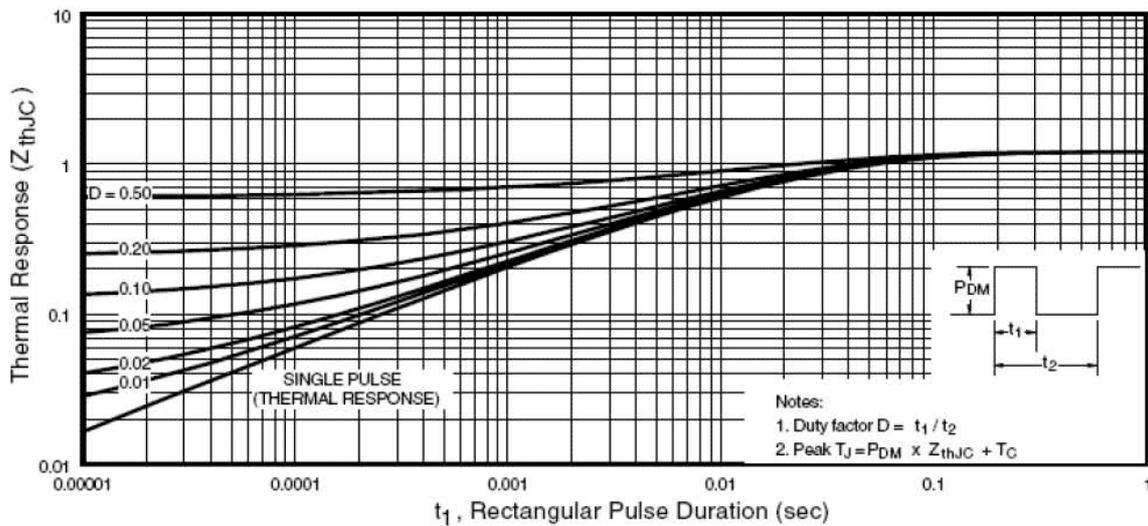


Fig. 6 – Maximum Effective Transient Thermal Impedance, Junction-to-Case

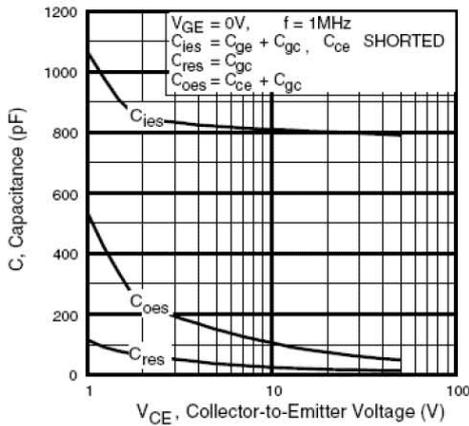


Fig.7 – Typical Capacitance vs. Collector-to-Emitter Voltage

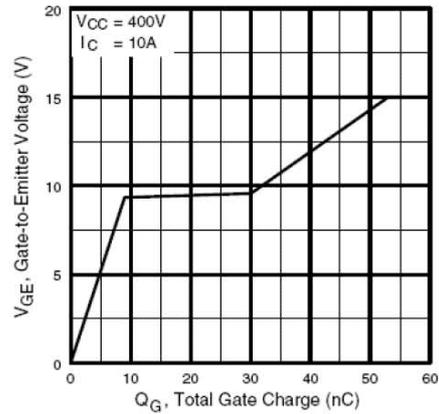


Fig.8- Typical Gate Charge vs. Gate-to-Emitter Voltage

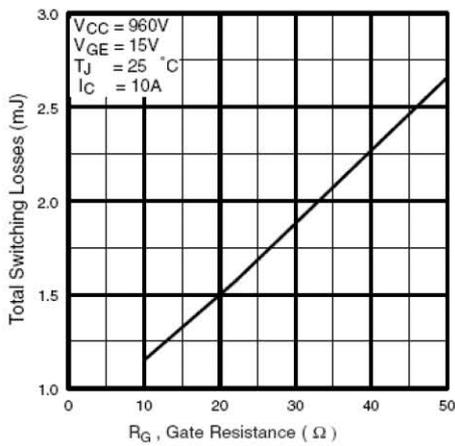


Fig.9 – Typical Switching Losses vs. Gate Resistance

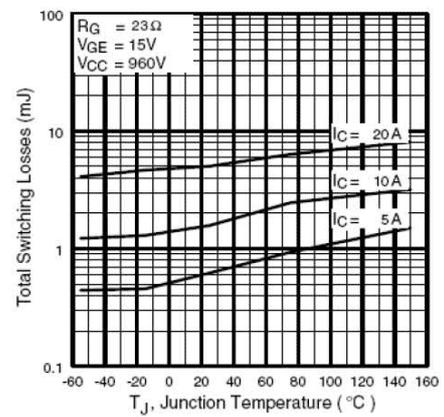


Fig. 10 – Typical Switching Losses vs. Junction Temperature

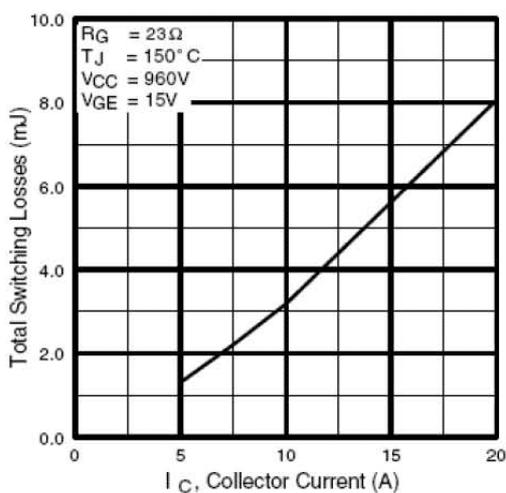


Fig. 11 – Typical Switching Losses vs. Collector-to-Emitter Current

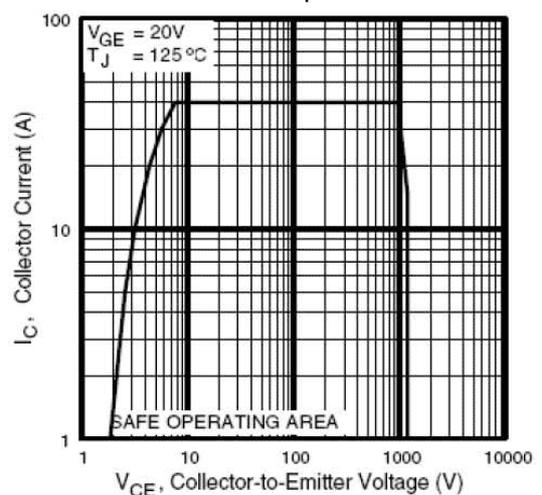
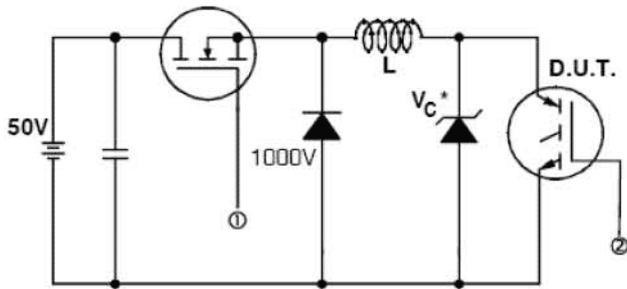


Fig. 12 – Turn-Off SOA



* Driver same type as D.U.T.; $V_c = 80\%$ of $V_{ce(max)}$
* Note: Due to the 50V power supply, pulse width and inductor will increase to obtain rated I_d .

Fig. 13a – Clamped Inductive Load Test Circuit

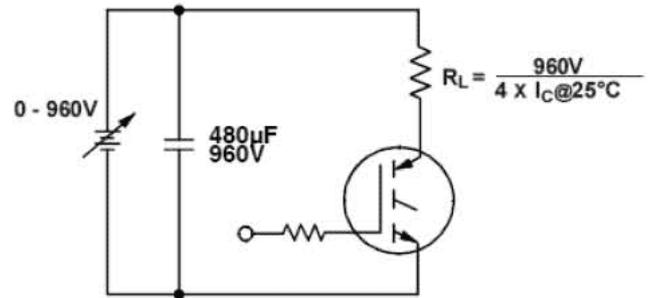


Fig.13b-Pulsed Collector Current Test Circuit

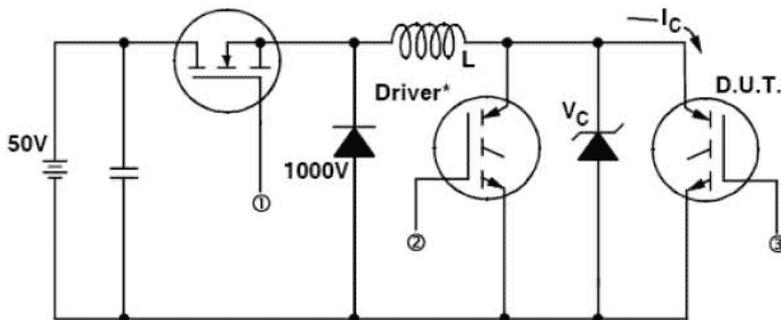


Fig. 14a - Switching Loss Test Circuit

* Driver same type as D.U.T., $V_c = 960V$

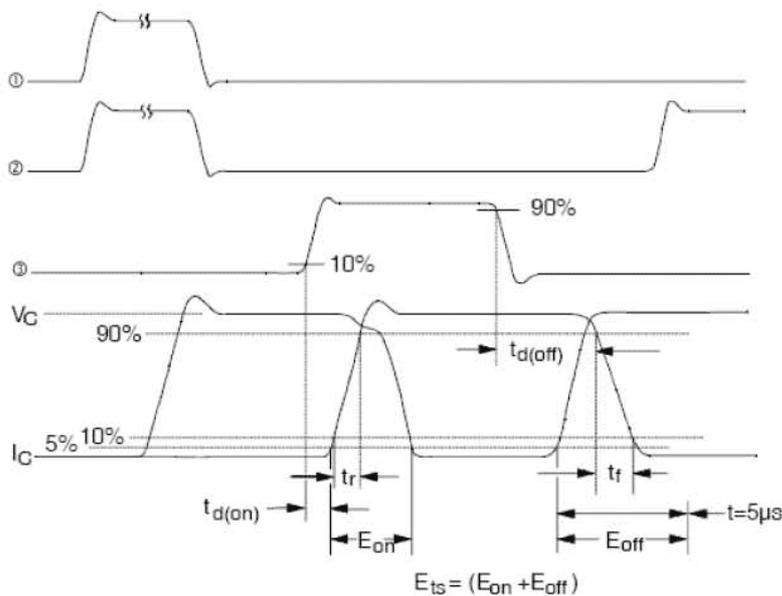


Fig. 14b - Switching Loss Waveforms